

TABLE 1 - LOT SAMPLING PLAN

Test/Inspection	Minimum Sample Size		Level
	Lot Size 200 or greater Devices	Lot Size 1-199 Devices (See NOTE 1)	
Minimum Required Tests			Level A
Documentation and Packaging			A1
Documentation and Packaging Inspection (4.2.6.4.1) (non-destructive)	All devices	All devices	
External Visual Inspection			A2
a. General (4.2.6.4.2.1) (non-destructive)	All devices	All devices	
b. Detailed (4.2.6.4.2.2) (non-destructive)	122 devices	122 or all devices, whichever is less	
Remarking & Resurfacing (destructive)	See NOTE 2	See NOTE 2	A3
Solvent Test for Remarking (4.2.6.4.3 A) (destructive)	3 devices	3 devices	
Solvent Test for Resurfacing (4.2.6.4.3 B) (destructive)	3 devices	3 devices	
Radiological (X-Ray) Inspection			A4
X-Ray Inspection (4.2.6.4.4) (non-destructive)	45 devices	45 devices or all devices, whichever is less	
Lead Finish Evaluation (XRF or EDS/EDX)	See NOTE 3	See NOTE 3	A5
XRF (non-destructive) or EDS/EDX (destructive) (4.2.6.4.5) (Appendix C.1)	3 devices	3 devices	
Delid/Decapsulation Internal Analysis (destructive)	See NOTE 4	See NOTE 4	A6
Delid/Decapsulation (4.2.6.4.6) (destructive)	3 devices	3 devices	
Additional Tests (as agreed between Customer and Organization)			
Remarking & Resurfacing (destructive)	See NOTE 2	See NOTE 2	A3 Option
Scanning Electron Microscope (4.2.6.4.3 C) (destructive)	3 devices	3 devices	
Quantitative Surface Analysis (4.2.6.4.3 D) (non-destructive)	5 devices	5 devices	
Thermal Testing			Level B
Thermal Cycling Test (Appendix C.2)	All devices	All devices	
Electrical Testing			Level C
Electrical Testing (Appendix C.3)	116 devices	All devices	
Burn-In			Level D
Burn-In (Pre & Post) (Appendix C.4)	45 Devices	45 devices or all devices, whichever is less	
Hermeticity Verification (Fine and Gross Leak)			Level E
Hermeticity Verification (Fine and Gross Leak) (Appendix C.5)	All devices	All devices	
Scanning Acoustic Microscopy (SAM)			Level F
Scanning Acoustic Microscopy (SAM) (Appendix C.6)	As specified	As specified	
Other			Level G
Other test/inspections	As specified	As specified	

NOTES:

- For very small lot sizes, less than ten (10) devices, this "destruct" test sample size may be reduced to one (1) device at the discretion of the Cognizant Engineer with Quality Assurance concurrence and Customer approval.
- Devices for the Remarking & Resurfacing Inspection shall be selected from the Detailed External Visual Inspection lot.
- Devices with possible lead finish anomalies shall be selected from the Detailed External Visual Inspection lot.
- Devices for the Delid/Decapsulation Internal Analysis shall be selected from the Remarking & Resurfacing Inspection lot.